

Total Internal Reflection Ellipsometry of Au/SiO_xN_y Waveguide Structures for Sensor Applications

Juraj Chlpík^{1, a)}, Soňa Kováčová², Ľuboš Podlucký², Martin Ziman²,
Martin Feiler², Soňa Kotorová¹, Jaroslav Kováč Jr.², Tomáš Váry¹
and Július Cirák¹

¹*Institute of Nuclear and Physical Engineering, Faculty of Electrical Engineering and Information Technology,
Slovak University of Technology in Bratislava, Ilkovičova 3, SK-812 19, Bratislava, Slovakia,*

²*Institute of Microelectronics and Photonics, Faculty of Electrical Engineering and Information Technology,
Slovak University of Technology in Bratislava, Ilkovičova 3, SK-812 19, Bratislava, Slovakia.*

^{a)} *Corresponding author: juraj.chlpik@stuba.sk*

From technical reasons not available.